

RELIABILITY DATA					
ASEK 2nd SOURCE QUALIFICATION DATA					
2/14/2019					
• J-STD-020 MSL 3 PRECONDITIONING: 192h +30°C/60%R.H. SOAK, 3x REFLOW AT +245°C PEAK					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE		NUMBER OF FAILURES
LTM8026	285 285	1812	1812		0 0
• EXTENDED PRECONDITIONING: 216h +30°C/60%R.H. SOAK, 3x REFLOW AT +245°C PEAK					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE		NUMBER OF FAILURES
LTM8026	50 50	1812	1812		0 0
• HIGH TEMPERATURE STORAGE +150°C					
DEVICE	SAMPLE	OLDEST	NEWEST	K DEVICE HOURS AT +150°C	NUMBER OF
LTM8026	45 45	1812	1812	90.00 90.00	0 0
• TEMP CYCLE FROM -55°C to +125°C ⁽¹⁾					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
LTM8026	95 95	1812	1812	190.00 190.00	0 0
• THERMAL SHOCK FROM -55°C to +125°C ⁽¹⁾					
DEVICE	SAMPLE	OLDEST	NEWEST	K DEVICE	NUMBER OF
LTM8026	83 83	1812	1812	166.00 166.00	0 0
• UNBIASED HIGHLY ACCELERATED STRESS TEST +130°C/85% R.H. ⁽¹⁾					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS AT +130°C	NUMBER OF FAILURES
LTM8026	92 92	1812	1812	8.83 8.83	0 0
(1) Environmental stress are preceded by J-STD-020 Preconditioning					

Sample of Top Mark on LTM8026

